PCN Number: 2023033						331000.1 P			CN Date:		March 31, 2023	
Title	-	-			al F	ab site (RFAB) a	nd add	Cu a	as a	lternati	ve Wire Base Metal	
for Selected Device(s)												
Customer Contact: PCN Ma					ana	<u>ger</u>		Dep	pt:		Quality Services	
Proposed 1 st Ship Date: June 3					0, 2	023 Sample requests accepted until:			Apr 30, 2023*			
*Sample requests received after Apr 30, 2023 will not be supported.												
Change Type:												
Assembly Site					Design				Wafer Bump Material			
Assembly Process					Data Sheet				Wafer Bump Process			
Assembly Materials					Part number change			\boxtimes	Wafer Fab Site			
Mechanical Specification					Test Site			\boxtimes	Wafer Fab Materials			
Packing/Shipping/Labeling						Test Process			Wafer Fab Process			
	PCN Details											

Description of Change:

Texas Instruments is pleased to announce the qualification of an additional fab (RFAB) and add Cu as alternative Wire Base Metal for selected devices as listed below in the product affected section.

C	urrent Fab Site	9	Additional Fab Site				
Current Fab Site	Process	Wafer Diameter	Additional Fab Site	Process	Wafer Diameter		
DMOS5	LBC7	200 mm	RFAB	LBC7	300 mm		

Construction differences are as follows:

	Current	Proposed
Bond wire composition	0.96mil Au	1.0 mil Cu

Qual details are provided in the Qual Data Section.

Reason for Change:

Continuity of Supply

- 1) To align with world technology trends and use wiring with enhanced mechanical and electrical properties
- 2) Maximize flexibility within our Assembly/Test production sites.

3) Cu is easier to obtain and stock

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):

None

Impact on Environmental Ratings:

Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.

	REACH	Green Status	IEC 62474
🛛 No Change 🛛	No Change	🛛 No Change	🛛 No Change

Changes to product identification resulting from this PCN:									
Fab Site Information:									
Chip Site	Chip Site Origin Code (20L)	Chip Site Country Code (21L)	Chip Site City						
DMOS5	DM5	USA	Dallas						
RFAB	RFB	USA	Richardson						
Sample product shipping label (not actual product label) TEXAS INSTRUMENTS MADE IN: Malaysia 20: MSL 2 /260C/1 YEAR SEAL DT MSL 1 /235C/UNLIM 03/29/04 OPT: ITEM: BL: 5A (L)T0:1750 (01 P) SN74LS07NSR (Q) 2000 (D) 0336 (31 T)LOT: 3959047MLA (4W) TKY (1T) 7523483S12 (P) (2D) CS0: SHE (21L) CC0:USA (21L) CC0:USA									
Group 1 Product Affect	ted: (Wafer Fab + Cu	wire)							
UCC28951PWR UCC28951PWT									
Group 2 Product Affect	ted: (Cu wire only)								
UCC28950PW UCC28950PWR									

Qualification Report Approve Date 15-Mar-2023

	Data Displayed as: Number of lots / Total sample size / Total failed											
Түре		Test Name	Condition	Duration	Qual Device: UCC28950PWR	Qual Device: UCC28951PWR	QBS Process Reference: <u>SN3257</u> Q <u>DYYRQ1</u>	QBS Package Reference: ADS1230IPW	QBS Package Reference: <u>THS7303PW</u>	QBS Process Reference: <u>BQ51013B</u> Q <u>WRHLRQ1</u>	QBS Process Reference: TPS3702EX33QDDCRQ1	QBS Product/Process Reference: <u>UCC289510PWR01</u>
HAST	A2	Biased HAST	130C/85%RH	96 Hours	-	-	3/231/0	-	-	3/231/0	3/231/0	1/77/0
UHAST	A3	Autoclave	121C/15psig	384 Hours	-	-	-	3/231/0	3/231/0	-	-	-
UHAST	A3	Autoclave	121C/15psig	96 Hours	-	1/77/0	3/231/0	-	-	3/231/0	3/231/0	1/77/0
тс	A4	Temperature Cycle	-65C/150C	500 Cycles	-	1/77/0	3/231/0	3/231/0	3/231/0	3/231/0	3/231/0	1/77/0
HTSL	A6	High Temperature Storage Life	150C	1000 Hours	-	-	3/135/0	-	-	1/77/0	-	1/45/0
HTSL	A6	High Temperature Storage Life	170C	1000 Hours	-	-	-	-	3/231/0	-	-	-
HTSL	A6	High Temperature Storage Life	170C	420 Hours	-	-	-	3/231/0	-	-	-	-
HTOL	B1	Life Test	125C	1000 Hours	-	-	-	-	-	3/231/0	3/231/0	1/77/0
HTOL	B1	Life Test	150C	300 Hours	-	-	3/231/0	-	-	-	-	-
ELFR	B2	Early Life Failure Rate	150C	24 Hours	-	-	3/2400/0	-	-	-	-	-

Qualification Results

Texas Instruments Incorporated

WBP	C2	Bond Pull	76 Wires, 3 units min	Wires	-	1/76/0	-	-	-	-	-	-
SD	C3	PB Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0	-		1/15/0	2/30/0	1/15/0
SD	C3	PB-Free Solderability	Precondition w.155C Dry Bake (4 hrs +/- 15 minutes)	-	-	-	1/15/0		-	1/15/0	2/30/0	1/15/0
PD	C4	Physical Dimensions	Cpk>1.67	-	-	-	3/30/0	-	-	3/30/0	3/30/0	3/30/0
ESD	E2	ESD CDM	-	1500 Volts	-	1/3/0	-	-	-	-	-	-
ESD	E2	ESD HBM	-	4000 Volts	-	1/3/0	-	-	-	-	-	-
LU	E4	Latch-Up	Per JESD78	-	-	1/3/0	1/6/0	-	-	1/6/0	1/6/0	1/6/0
CHAR	E5	Electrical Characterization	Per Datasheet Parameters	-	-	1/30/0	3/90/0	-	-	3/90/0	3/90/0	3/90/0
FTY	E6	Final Test Yield	-	-	-	1/1/0	-	-	-	-	-	-
SAM		SAM Post Temperature Cycle	-	-	-	1/12/0	-	-	-	-	-	-

QBS: Qual By Similarity

Qual Device UCC28950PWR is qualified at MSL1 260C

Qual Device UCC28951PWR is qualified at MSL2 260C

Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality

and Environmental data is available at TI's external Web site: <u>http://www.ti.com/</u> Green/Pb-free Status: Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the contact below or your local Field Sales Representative.

Location	E-Mail					
WW Change Management Team	PCN ww admin team@list.ti.com					

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